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FORM PTO-1449		U.S. Department of Commerce Patent and Trademark Office		Atty. Docket No. P29884	Application No. 10/577,305
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		Applicant Dieter LEHMANN et al.			
		I.A. Filing Date October 22, 2004		Group Unknown	

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/S.B./		5 5 7 6 1 0 6	11/19/96	KERBOW et al.			
/S.B./		4 8 3 5 1 3 0	05/24/83	MOLINSKI et al.			
/S.B./		3 2 9 8 9 4 2	05/20/58	MAGAT et al.			
/S.B./		6 3 8 7 9 6 4	05/14/02	D'AGOSTINO et al.			
/S.B./		6 2 2 5 3 6 8	05/01/01	D'AGOSTINO et al.			
/S.B./		5 7 5 6 1 9 9	05/26/98	KERBOW et al.			
/S.B./		6 7 7 0 3 7 8	08/03/04	LEHMANN			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLAS S	SUBCLASS	TRANSLATION YES NO
/S.B./		1 5 1 6 6 4 8	07/05/78	GREAT BRITAIN			
/S.B./		9 6 / 0 3 4 4 8	02/08/96	W.I.P.O.			
		1 4 6 7 1 6	10/22/79	GERMANY			
/S.B./		2 3 1 8 8 9 6	02/18/77	FRANCE			
/S.B./	2004	- 1 0 7 4 6 1	04/08/04	JAPAN			
/S.B./	1	9 8 2 3 6 0 9	12/02/99	GERMANY			
/S.B./	9	9 / 6 1 5 2 7	12/02/99	W.I.P.O.			
/S.B./	63	- 0 0 7 4 5 5	01/13/88	JAPAN			
		3 4 9 4 7 0 2	05/28/82	FRANCE			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

/S.B./	1	A. Heger et al., Technologie der Strahlenchemie an Polymeren, Akademie-Verlag Berlin 1990, 463-488 and 496-501.
/S.B./	2	Ferse et al., Plaste u. Kautschuk, 29 (1982), 45-465.
/S.B./	3	K. Schierholz et al., J. Polym. Sci. Part B, Polymer Physics, Vol. 37, 2404-2411 (1999).
/S.B./	4	English Language Abstract of FR 2318896.
/S.B./	5	English Language Abstract of JP 2004-107461.
/S.B./	6	Dargaville et al., "High Energy Radiation Grafting Of Fluoropolymers", Prog. Poly. Sci. 28 (2003) 1355-1376.
/S.B./	7	English Language Abstract of JP 63-007455.
/S.B./	8	Patent Abstracts of Japan, Vol. 011, No. 222 (C-435), July 18, 1987
/S.B./	9	Patent Abstracts of Japan, Vol. 2003, No. 03, May 5, 2003
/S.B./	10	Patent Abstracts of Japan, Vol. 014, No. 252 (E-0934), May 20, 1990

EXAMINER /Susan Berman/ DATE CONSIDERED 01/16/2009

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.